# 74LV125

# Quad buffer/line driver; 3-state Rev. 03 — 7 April 2009

**Product data sheet** 

#### 1. **General description**

The 74LV125 is a low-voltage Si-gate CMOS device that is pin and function compatible with 74HC125 and 74HCT125.

The 74LV125 provides four non-inverting buffer/line drivers with 3-state outputs. The 3-state outputs (nY) are controlled by the output enable input ( $n\overline{OE}$ ). A HIGH at  $n\overline{OE}$ causes the outputs to assume a high-impedance OFF-state.

#### 2. **Features**

- Wide operating voltage: 1.0 V to 5.5 V
- Optimized for low voltage applications: 1.0 V to 3.6 V
- Accepts TTL input levels between V<sub>CC</sub> = 2.7 V and V<sub>CC</sub> = 3.6 V
- Typical output ground bounce < 0.8 V at  $V_{CC}$  = 3.3 V and  $T_{amb}$  = 25 °C
- Typical HIGH-level output voltage (V<sub>OH</sub>) undershoot: > 2 V at V<sub>CC</sub> = 3.3 V and  $T_{amb} = 25 \, ^{\circ}C$
- ESD protection:
  - HBM JESD22-A114E exceeds 2000 V
  - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

# Ordering information

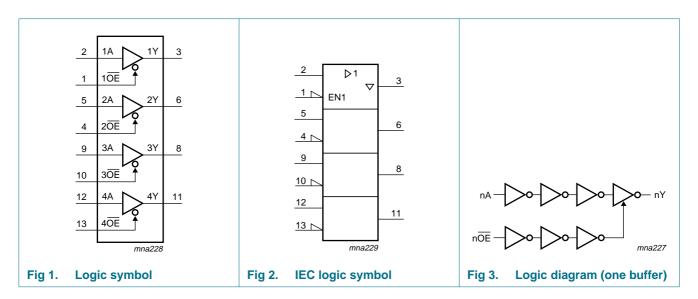
Table 1. **Ordering information** 

Type number	Package			
	Temperature range	Name	Description	Version
74LV125N	–40 °C to +125 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1
74LV125D	–40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1
74LV125DB	–40 °C to +125 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1
74LV125PW	–40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1



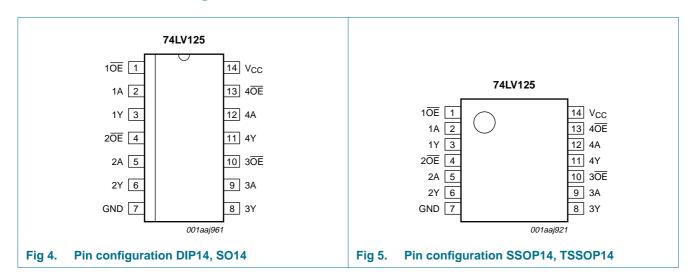
Quad buffer/line driver; 3-state

# 4. Functional diagram



# 5. Pinning information

### 5.1 Pinning



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### 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
$1\overline{OE}$ , $2\overline{OE}$ , $3\overline{OE}$ , $4\overline{OE}$ ,	1, 4, 10, 13	output enable input (active LOW)
1A, 2A, 3A, 4A	2, 5, 9, 12	data input
1Y, 2Y, 3Y, 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V <sub>CC</sub>	14	supply voltage

# 6. Functional description

Table 3. Function table[1]

Control	Input	Output
nŌĒ	nA	nY
L	L	L
L	Н	Н
Н	X	Z

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+7.0	V
I <sub>IK</sub>	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$	[1] _	±20	mA
I <sub>OK</sub>	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$	<u>[1]</u> _	±50	mA
I <sub>O</sub>	output current	$V_{O} = -0.5 \text{ V to } (V_{CC} + 0.5 \text{ V})$	-	±35	mA
I <sub>CC</sub>	supply current		-	70	mA
$I_{GND}$	ground current		<b>-70</b>	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C}$	[2]		
		DIP14	-	750	mW
		SO14, SSOP14, TSSOP14	-	500	mW

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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<sup>[2]</sup> For DIP14 packages: above 70 °C the value of  $P_{tot}$  derates linearly with 12 mW/K. For SO14 packages: above 70 °C the value of  $P_{tot}$  derates linearly with 8 mW/K. For (T)SSOP14 packages: above 60 °C the value of  $P_{tot}$  derates linearly with 5.5 mW/K.

Quad buffer/line driver; 3-state

# 8. Recommended operating conditions

Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{CC}$	supply voltage[1]		1.0	3.3	5.5	V
VI	input voltage		0	-	$V_{CC}$	V
Vo	output voltage		0	-	$V_{CC}$	V
T <sub>amb</sub>	ambient temperature		-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 1.0 \text{ V to } 2.0 \text{ V}$	-	-	500	ns/V
		$V_{CC} = 2.0 \text{ V to } 2.7 \text{ V}$	-	-	200	ns/V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	-	-	100	ns/V
		$V_{CC} = 3.6 \text{ V to } 5.5 \text{ V}$	-	-	50	ns/V

<sup>[1]</sup> The static characteristics are guaranteed from  $V_{CC}$  = 1.2 V to  $V_{CC}$  = 5.5 V, but LV devices are guaranteed to function down to  $V_{CC}$  = 1.0 V (with input levels GND or  $V_{CC}$ ).

### 9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	35 °C	-40 °C to	Unit	
			Min	Typ[1]	Max	Min	Max	1
$V_{IH}$	HIGH-level input voltage	V <sub>CC</sub> = 1.2 V	0.9	-	-	0.9	-	V
		V <sub>CC</sub> = 2.0 V	1.4	-	-	1.4	-	V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2.0	-	-	2.0	-	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	$0.7V_{CC}$	-	-	$0.7V_{CC}$	-	V
$V_{IL}$	LOW-level input voltage	$V_{CC} = 1.2 \text{ V}$	-	-	0.3	-	0.3	V
		$V_{CC} = 2.0 \text{ V}$	-	-	0.6	-	0.6	V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	-	-	8.0	-	0.8	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	-	-	$0.3V_{CC}$	-	$0.3V_{CC}$	V
$V_{OH}$	HIGH-level output voltage	$V_I = V_{IH}$ or $V_{IL}$						
		$I_O = -100 \ \mu A; \ V_{CC} = 1.2 \ V$	-	1.2	-	-	-	V
		$I_{O} = -100 \ \mu A; \ V_{CC} = 2.0 \ V$	1.8	2.0	-	1.8	-	V
		$I_{O} = -100 \ \mu A; \ V_{CC} = 2.7 \ V$	2.5	2.7	-	2.5	-	V
		$I_O = -100 \ \mu A; \ V_{CC} = 3.0 \ V$	2.8	3.0	-	2.8	-	V
		$I_{O} = -100 \ \mu A; \ V_{CC} = 4.5 \ V$	4.3	4.5	-	4.3	-	V
		$I_{O} = -8 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.4	2.82	-	2.2	-	V
		$I_O = -16 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.6	4.2	-	3.5	-	V

Quad buffer/line driver; 3-state

 Table 6.
 Static characteristics ...continued

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	-40 °C to	+125 °C	Unit
			Min	Typ[1]	Max	Min	Max	
$V_{OL}$	LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$				•		
		$I_O = 100 \mu A; V_{CC} = 1.2 V$	-	0	-	-	-	V
		$I_O = 100 \mu A; V_{CC} = 2.0 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 2.7 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 3.0 V$	-	0	0.2	-	0.2	V
		$I_O = 100 \mu A; V_{CC} = 4.5 V$	-	0	0.2	-	0.2	V
		$I_O = 8 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	0.20	0.40	-	0.50	V
		$I_{O}$ = 16 mA; $V_{CC}$ = 4.5 V	-	0.35	0.55	-	0.65	V
l <sub>l</sub>	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 5.5 \text{ V}$	-	-	1.0	-	1.0	μΑ
l <sub>OZ</sub>	OFF-state output current	$V_I = V_{IH}$ or $V_{IL}$ ; $V_O = V_{CC}$ or GND; $V_{CC} = 5.5 \text{ V}$	-	-	5	-	10	μΑ
I <sub>CC</sub>	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 5.5 \text{ V}$	-	-	20	-	160	μΑ
$\Delta I_{CC}$	additional supply current	per input; $V_I = V_{CC} - 0.6 \text{ V}$ ; $V_{CC} = 2.7 \text{ V}$ to 3.6 V	-	-	500	-	850	μΑ
C <sub>I</sub>	input capacitance		-	3.5	-	-	-	pF

<sup>[1]</sup> Typical values are measured at  $T_{amb}$  = 25 °C.

# 10. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 8.

Symbol	Parameter	Conditions		<b>-40</b>	°C to +85	5 °C	-40 °C to +125 °C		Unit
				Min	Typ[1]	Max	Min	Max	
t <sub>pd</sub>	propagation delay	nA to nY; see Figure 6	[2]						
		V <sub>CC</sub> = 1.2 V		-	55	-	-	-	ns
		$V_{CC} = 2.0 \text{ V}$		-	19	24	-	31	ns
		$V_{CC} = 2.7 \text{ V}$		-	14	18	-	23	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V; } C_L = 15 \text{ pF}$	[3]	-	9	-	-	-	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	[3]	-	10	14	-	18	ns
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-	-	12	-	15	ns
$t_{en}$	enable time	nOE to nY; see Figure 7	[2]						
		V <sub>CC</sub> = 1.2 V		-	75	-	-	-	ns
		$V_{CC} = 2.0 \text{ V}$		-	26	31	-	39	ns
		$V_{CC} = 2.7 \text{ V}$		-	19	23	-	29	ns
		$V_{CC}$ = 3.0 V to 3.6 V	[3]	-	14	18	-	23	ns
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-	-	15	-	19	ns

Quad buffer/line driver; 3-state

 Table 7.
 Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 8.

Symbol	Parameter	Conditions		<b>-40</b>	°C to +85	S°C	–40 °C t	o +125 °C	Unit
				Min	Typ[1]	Max	Min	Max	
t <sub>dis</sub>	disable time	nOE to nY; see Figure 7	[2]						
		V <sub>CC</sub> = 1.2 V		-	65	-	-	-	ns
		V <sub>CC</sub> = 2.0 V		-	24	32	-	39	ns
		V <sub>CC</sub> = 2.7 V		-	18	24	-	29	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	[3]	-	14	20	-	24	ns
		V <sub>CC</sub> = 4.5 V to 5.5 V		-	-	17	-	21	ns
$C_{PD}$	power dissipation capacitance	$C_L = 50 \text{ pF}; f_i = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}; V_{CC} = 3.3 \text{ V}$	[4]	-	22	-	-	-	pF

- [1] All typical values are measured at  $T_{amb}$  = 25 °C.
- $\begin{array}{ll} [2] & t_{pd} \text{ is the same as } t_{PLH} \text{ and } t_{PHL}. \\ & t_{en} \text{ is the same as } t_{PZL} \text{ and } t_{PZH}. \\ & t_{dis} \text{ is the same as } t_{PLZ} \text{ and } t_{PHZ}. \end{array}$
- [3] Typical values are measured at nominal supply voltage ( $V_{CC} = 3.3 \text{ V}$ ).
- [4]  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$  where:

 $f_I$  = input frequency in MHz,  $f_o$  = output frequency in MHz

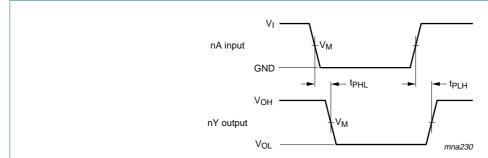
 $C_L$  = output load capacitance in pF

V<sub>CC</sub> = supply voltage in Volts

N = number of inputs switching

 $\Sigma(C_L \times V_{CC}^2 \times f_o)$  = sum of the outputs.

### 11. Waveforms



Measurement points are given in Table 8.

 $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical voltage output levels that occur with the output load.

Fig 6. The input (nA) to output (nY) propagation delays

### Quad buffer/line driver; 3-state

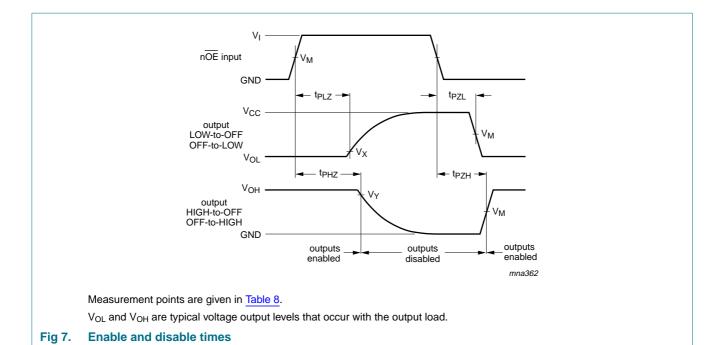
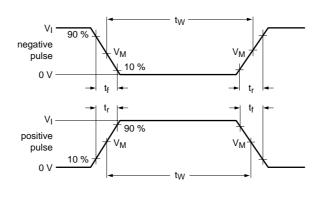
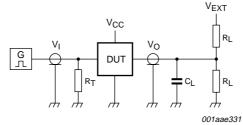


Table 8. Measurement points

Supply voltage	Input	Output	Output							
V <sub>CC</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>						
< 2.7 V	0.5V <sub>CC</sub>	0.5V <sub>CC</sub>	$V_{OL} + 0.1V_{CC}$	$V_{OH} - 0.1V_{CC}$						
2.7 V to 3.6 V	1.5 V	1.5 V	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V						
≥ 4.5 V	0.5V <sub>CC</sub>	0.5V <sub>CC</sub>	$V_{OL}$ + $0.1V_{CC}$	$V_{OH} - 0.1V_{CC}$						

### Quad buffer/line driver; 3-state





Test data is given in Table 9.

Definitions for test circuit:

R<sub>L</sub> = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to output impedance  $Z_0$  of the pulse generator.

 $V_{EXT}$  = External voltage for measuring switching times.

Fig 8. Load circuit for measuring switching times

Table 9. Test data

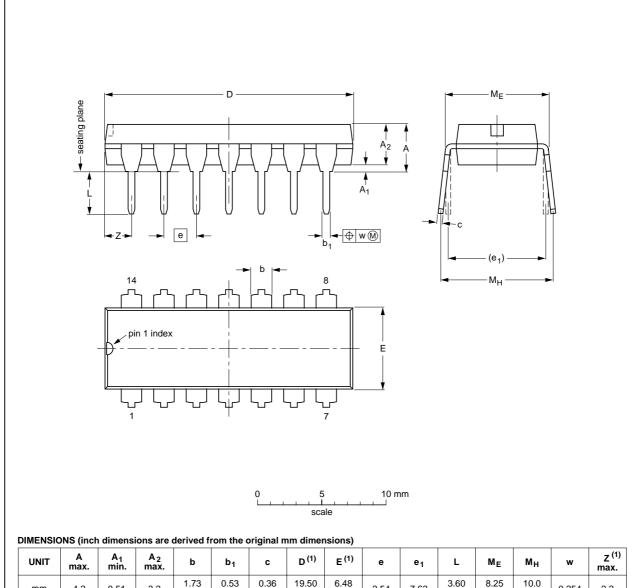
Supply voltage	Input		Load		V <sub>EXT</sub>			
V <sub>CC</sub>	VI	t <sub>r</sub> , t <sub>f</sub>	CL	R <sub>L</sub>	t <sub>PHL</sub> , t <sub>PLH</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>	
< 2.7 V	V <sub>CC</sub>	≤ 2.5 ns	50 pF	1 kΩ	open	GND	2V <sub>CC</sub>	
2.7 V to 3.6 V	2.7 V	≤ 2.5 ns	15 pF, 50 pF	1 kΩ	open	GND	2V <sub>CC</sub>	
≥ 4.5 V	$V_{CC}$	≤ 2.5 ns	50 pF	1 kΩ	open	GND	2V <sub>CC</sub>	

Quad buffer/line driver; 3-state

# 12. Package outline

### DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	e <sub>1</sub>	L	ME	Мн	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

#### Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

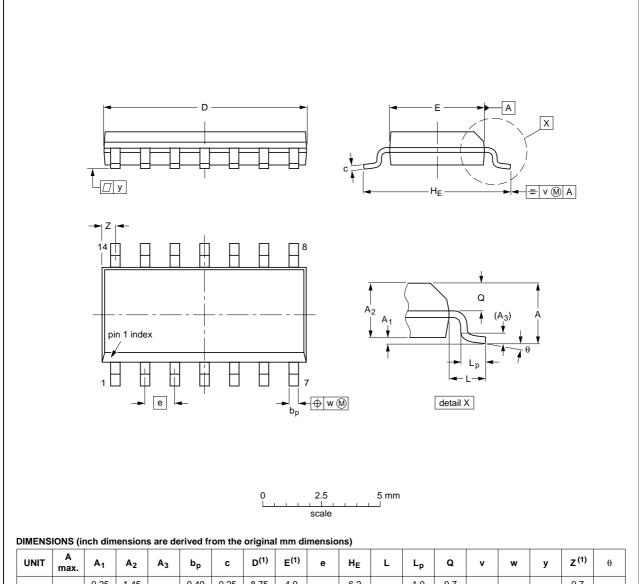
OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001	SC-501-14		<del>99-12-27</del> 03-02-13

Fig 9. Package outline SOT27-1 (DIP14)

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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01	l	0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012			<del>99-12-27</del> 03-02-19

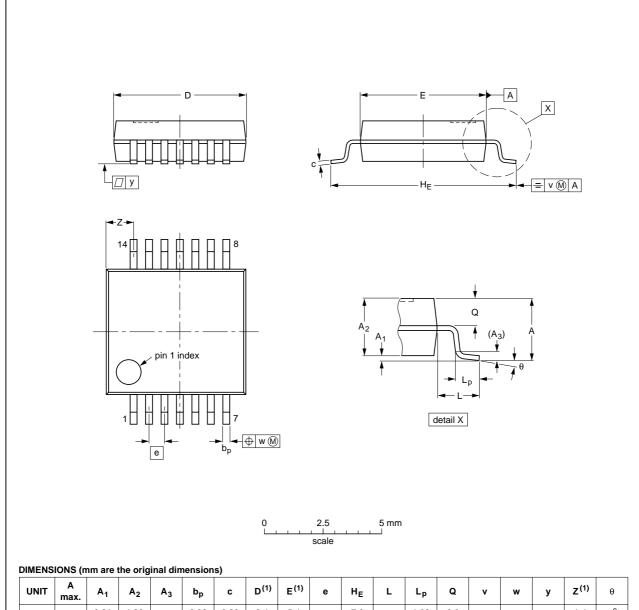
Fig 10. Package outline SOT108-1 (SO14)

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SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	ø	v	w	у	z <sup>(1)</sup>	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.4 0.9	8° 0°

#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT337-1		MO-150			<del>-99-12-27</del> 03-02-19

Fig 11. Package outline SOT337-1 (SSOP14)

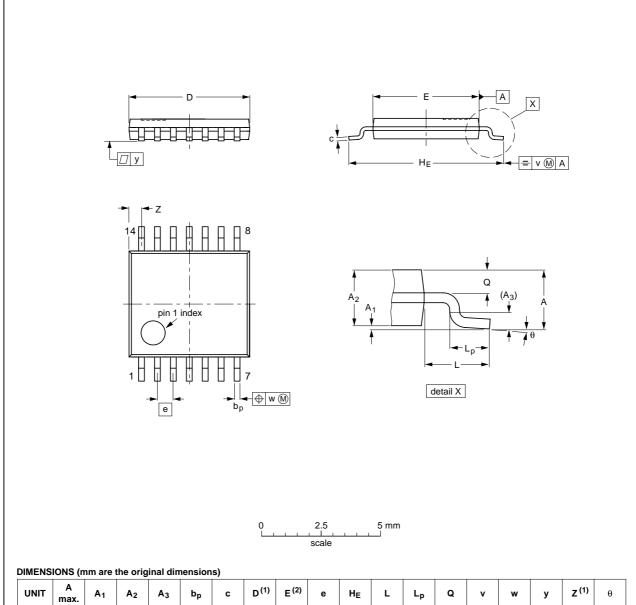
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74LV125 **NXP Semiconductors** 

Quad buffer/line driver; 3-state

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



	Α.							(-)										
UNIT	max.	A <sub>1</sub>	A <sub>2</sub>	Α3	bp	С	D <sup>(1)</sup>	E <sup>(2)</sup>	е	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

VERSION IEC JEDEC JEITA PROJECTION	OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
SOT402-1 MO-153 <del>99-12-27</del> 03-02-18	VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
_ \$\psi\$ 00.02.10	SOT402-1		MO-153			<del>99-12-27</del> 03-02-18

Fig 12. Package outline SOT402-1 (TSSOP14)

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Quad buffer/line driver; 3-state

# 13. Abbreviations

### Table 10. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

# 14. Revision history

### Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74LV125_3	20090407	Product data sheet	-	74LV125_2
Modifications:	<ul> <li>The format of this of NXP Semicond</li> </ul>	data sheet has been redeuctors.	esigned to comply with the	e new identity guidelines
	<ul> <li>Legal texts have b</li> </ul>	een adapted to the new o	ompany name when app	ropriate.
74LV125_2	19980428	Product specification	-	74LV125_1
74LV125_1	19970203	Product specification	-	-

Quad buffer/line driver; 3-state

# 15. Legal information

#### 15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
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### Quad buffer/line driver; 3-state

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